

# N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	200				
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V 0. 91				
Q <sub>g</sub> (Max.) (nC)	13				
Q <sub>gs</sub> (nC)	3.0				
Q <sub>gd</sub> (nC)	7.9				
Configuration	Single				

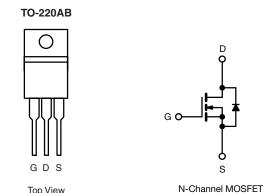
### **FEATURES**

- TrenchFET® Power MOSFET
- 175 °C Junction Temperature
- PWM Optimized
- 100 % R<sub>g</sub> Tested
- Compliant to RoHS Directive 2002/95/EC



### **APPLICATIONS**

· Primary Side Switch



PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	200	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C	I-	5.0	А	
Continuous Drain Current	VGS at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	4.0		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	20		
Linear Derating Factor				0.33	W/°C	
Linear Derating Factor (PCB Mount) <sup>e</sup>				0.020	]	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	161	mJ	
Repetitive Avalanche Current a			I <sub>AR</sub>	4.8	Α	
Repetitive Avalanche Energy a			E <sub>AR</sub>	4.2	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		Б	42	w	
Maximum Power Dissipation (PCB mount) <sup>e</sup>	T <sub>A</sub> = 25 °C		P <sub>D</sub>	2.5	7 vv	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	- °C	
Soldering Recommendations (Peak temperature) d	for 10 s			260		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=50~V$ , starting  $T_J=25~^{\circ}C$ , L=14~mH,  $R_g=25~\Omega$ ,  $I_{AS}=4.8~A$  (see fig. 12). c.  $I_{SD}\leq5.2~A$ ,  $dI/dt\leq95~A/\mu s$ ,  $V_{DD}\leq V_{DS}$ ,  $T_J\leq150~^{\circ}C$ .

Top View

- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	-	110		
Maximum Junction-to-Ambient (PCB mount) <sup>a</sup>	R <sub>thJA</sub>	-	-	50	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	-	3.0		

### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				L	l		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.29	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zana Oala Vallana Buria Oanaal	I <sub>DSS</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V		-	25	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 160 V	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 2.9 A <sup>b</sup>	-	0.91	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	50 V, I <sub>D</sub> = 2.9 A <sup>b</sup>	1.7	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,	=.	185	-	
Output Capacitance	C <sub>oss</sub>		$V_{GS} = 0 V$ , $V_{DS} = 25 V$ ,		100	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	30	-	
Total Gate Charge	$Q_g$			-	-	13.0	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 4.8 \text{ A}, V_{DS} = 160 \text{ V},$ see fig. 6 and 13 b		-	3.0	nC
Gate-Drain Charge	Q <sub>gd</sub>	see lig. 6 and 13		-	-	7.9	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 100 \text{ V, I}_D = 4.8 \text{ A,}$ $R_G = 18 \ \Omega, \ R_D = 20 \ \Omega, \ \text{see fig. } 10^{\text{ b}}$		-	7.2	-	ns
Rise Time	t <sub>r</sub>			-	22	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	19	-	
Fall Time	t <sub>f</sub>			-	13	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	الم
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						•
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.8	_
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	19	A
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25  ^{\circ}\text{C},  I_S = 4.8  \text{A},  V_{GS} = 0  \text{V}^{ \text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 4.8 A, dl/dt = 100 A/µs b		-	150	300	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.91	1.8	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )					Ln)

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

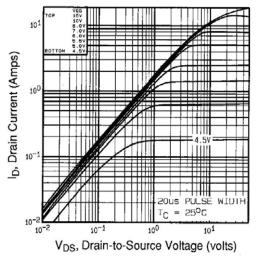


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

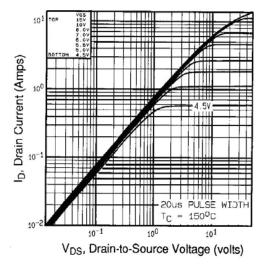


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

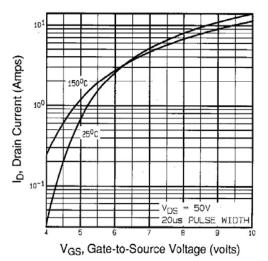


Fig. 3 - Typical Transfer Characteristics

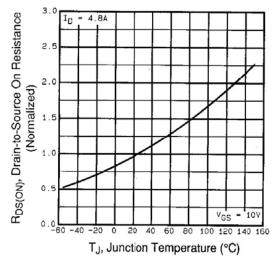


Fig. 4 - Normalized On-Resistance vs. Temperature



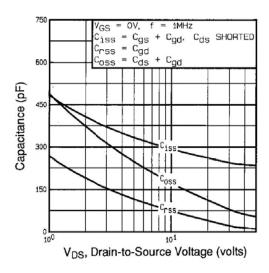


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

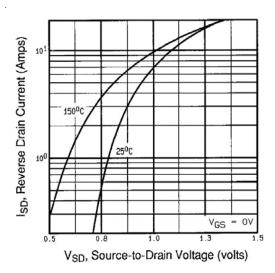


Fig. 7 - Typical Source-Drain Diode Forward Voltage

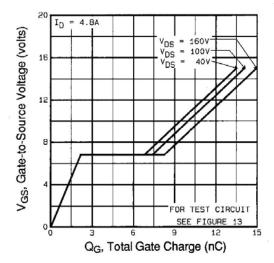


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

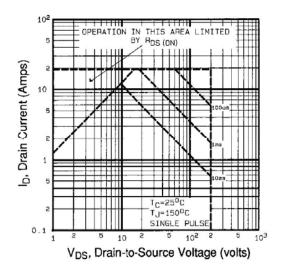


Fig. 8 - Maximum Safe Operating Area



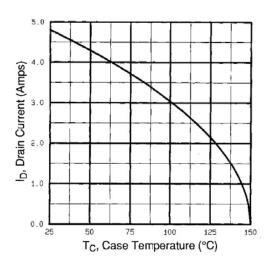


Fig. 9 - Maximum Drain Current vs. Case Temperature

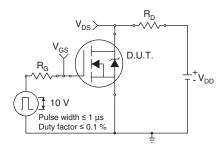


Fig. 10a - Switching Time Test Circuit

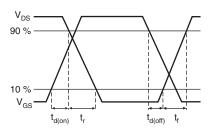


Fig. 10b - Switching Time Waveforms

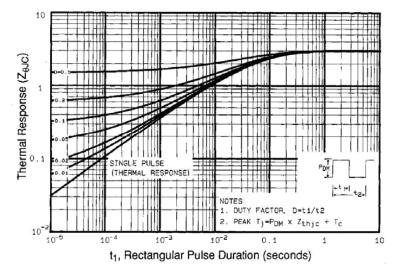


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



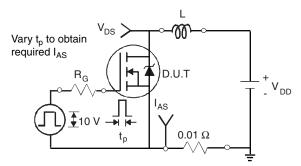


Fig. 12a - Unclamped Inductive Test Circuit

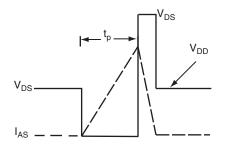


Fig. 12b - Unclamped Inductive Waveforms

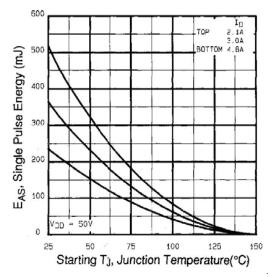


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

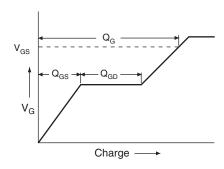


Fig. 13a - Basic Gate Charge Waveform

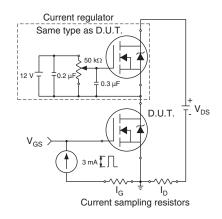
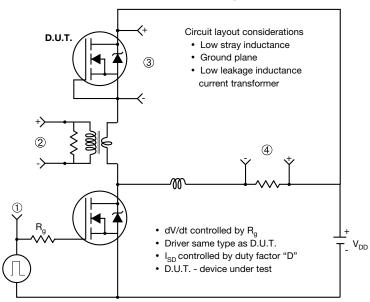


Fig. 13b - Gate Charge Test Circuit



## Peak Diode Recovery dV/dt Test Circuit



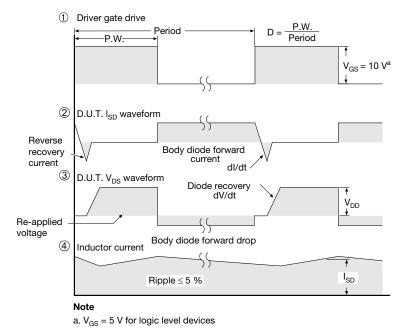
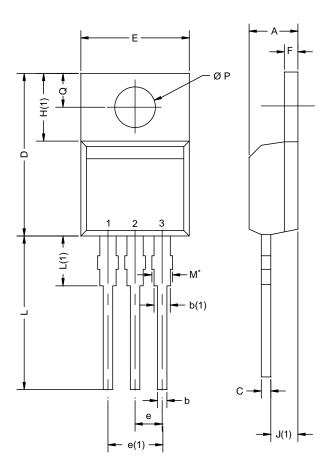


Fig. 14 - For N-Channel



# **TO-220AB**



	MILLIMETERS		INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØР	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471						

#### Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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